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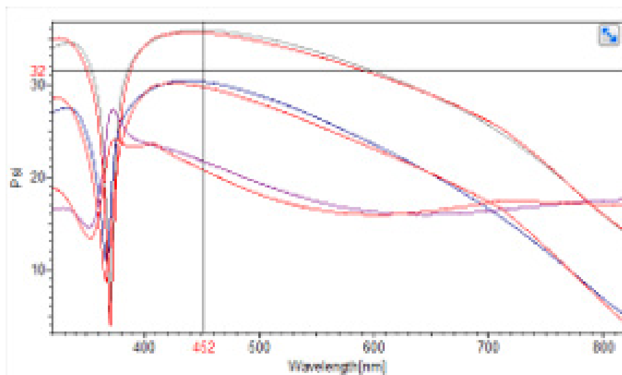
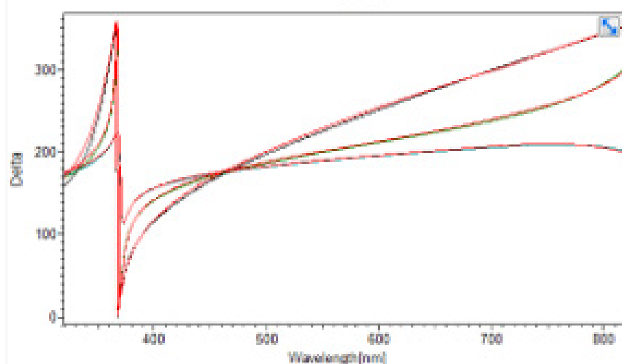
Instant Analysis

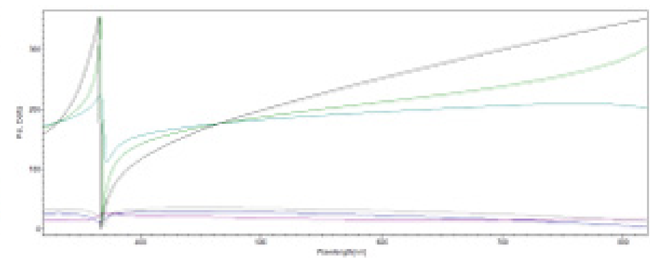
Sentech SE 801

The SE 801 Ellipsometer is a tool for measuring the optical properties (complex refractive index, film thickness) by measuring the change of polarization upon reflection of polarized light and comparing those measurements to a model.

Technical Data	
Spectral Range	370 – 1050 nm
Angle of Incident	40° - 85°, 5° Steps
Film Thickness	10 nm – several µm
Limitations Film Thickness Measurement	Basic Knowledge of all layers Transmission of all Layers >> 0 Reflectance of Substrate >> 0
Sample Size	Dia. 150 x 10 mm







Experiment No. 1		
Air		
Refr. index	☐	1,000
Absorption	☐	0,000
Cau-TiO2		
Thickness [nm]	☑	95,91
N0	☑	2,297
N1	☑	49,4
N2	☑	940,5
K0	☑	-0,149
K1	☑	995,148
K2	☑	-1247,327
Cau-SiO2 (therm.)		
Silicon VIS+NIR		

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